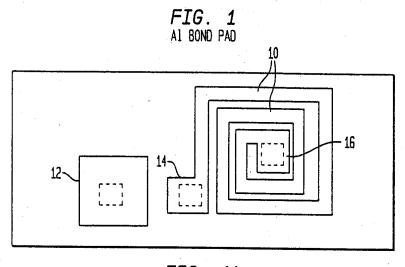
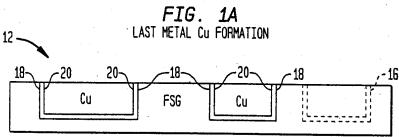
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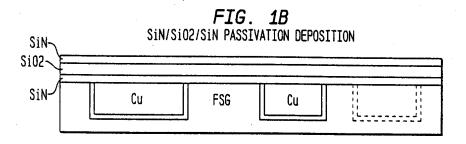


FIG. 1C TERMINAL VIA PATTERNING

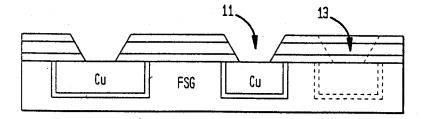
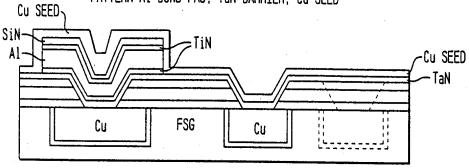


FIG. 1D
PATTERN AL BOND PAD. TAN BARRIER, CU SEED



 $\emph{FIG. 1E}$  resist pattern and cu plating for inductor

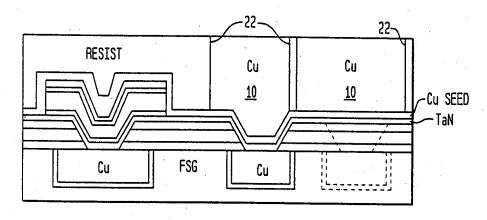


FIG. 1F
RESIST STRIP. CU ETCH, Tan ETCH, Cowp SELECTIVE DEP.

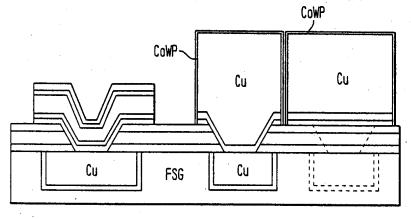


FIG. 1G
POLYMIDE APPLY, FINAL VIA OPENING

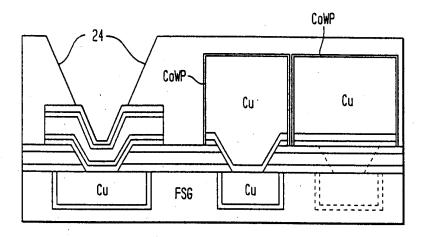
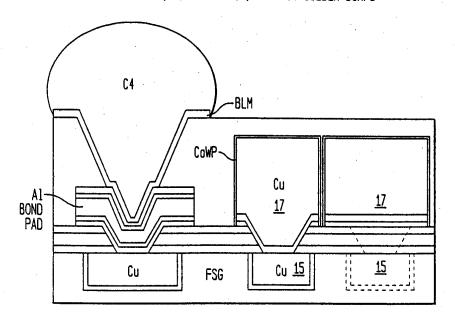


FIG. 1H ETCH SIN, DEP. BARRIER, FORM C4 SOLDER BUMPS



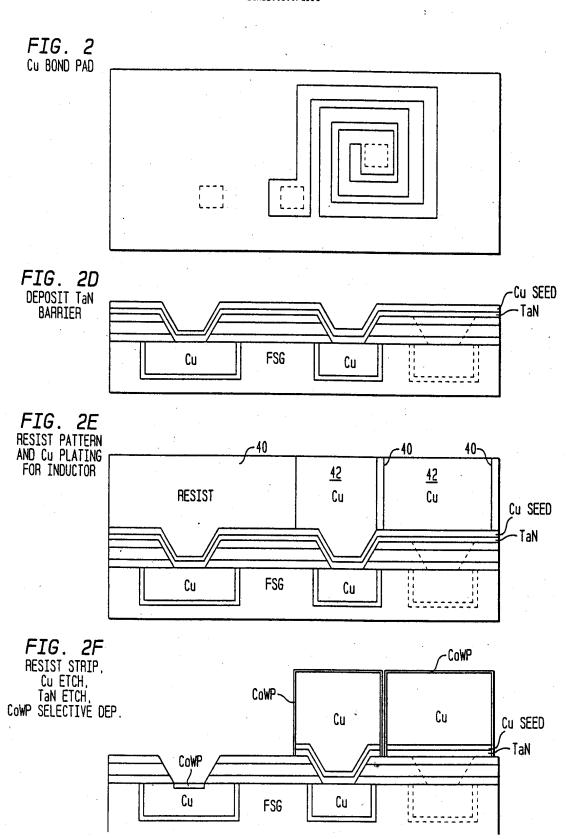


FIG. 2G
POLYIMIDE APPLY. FINAL VIA OPENING

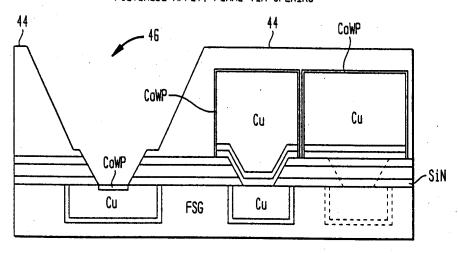


FIG. 2H
ETCH SIN, DEP. BARRIER, FORM C4 SOLDER BUMPS

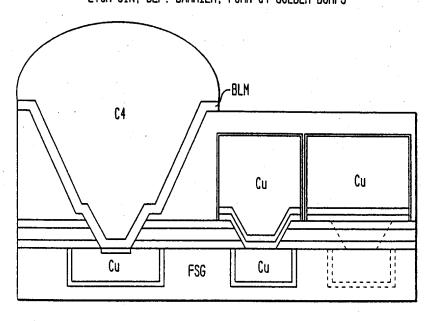


FIG. 3 RAISED CU BOND PAD

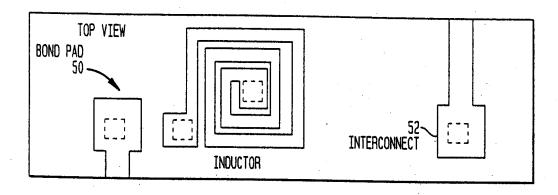


FIG. 3F
RESIST STRIP. TAN ETCH. COWP SELECTIVE DEP.

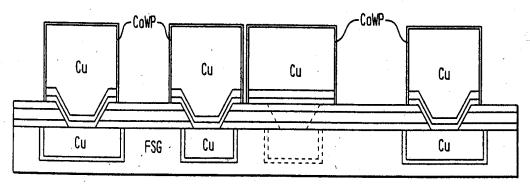


FIG. 3G
POLYIMIDE APPLY, FINAL VIA OPENING

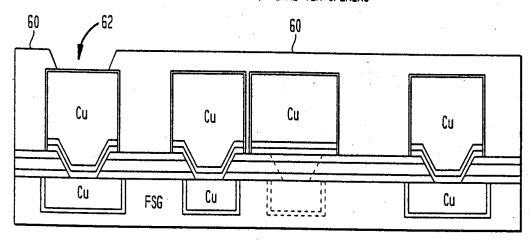


FIG. 3H ETCH SIN, DEP. BARRIER, FORM C4 SOLDER BUMPS

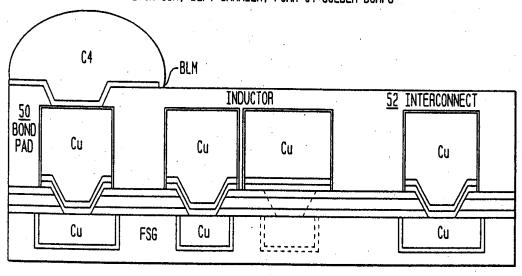


FIG. 4A
DEPOSIT TAN BARRIER AND CU SEED

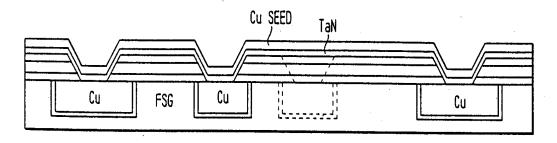


FIG. 4B RESIST PATTERN AND SELECTIVE Cu PLATING FOR INDUCTOR

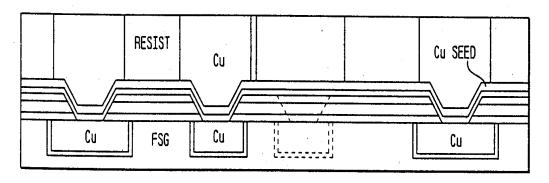


FIG. 4C STRIP RESIST, ETCH CU SEED AND BARRIER

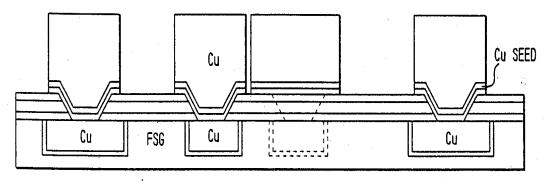
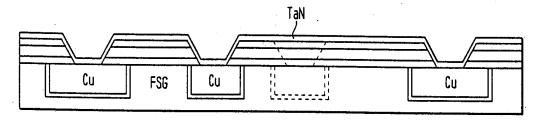


FIG. 5A DEPOSIT TAN BARRIER



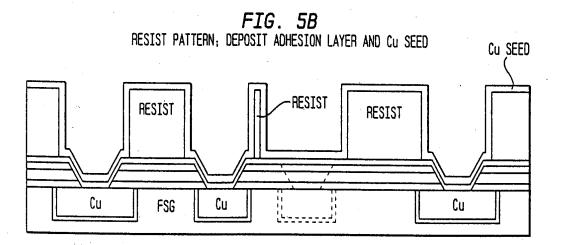


FIG. 5C Cu PLATING

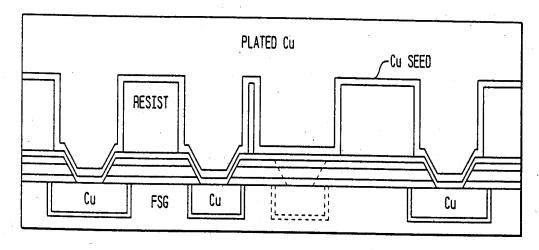


FIG. 5D
Cu CMP OR ELECTROPLATING
Cu SEED

Cu SEED

Cu SEED

Cu SEED

Cu Cu SEED

FIG. 5E RESIST STRIP AND BARRIER ETCH

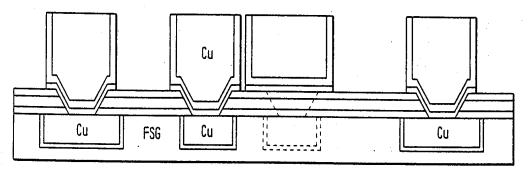
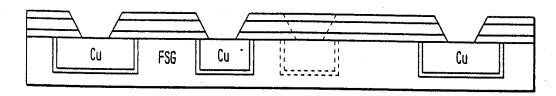


FIG. 6A
TERMINAL VIA PATTERNING



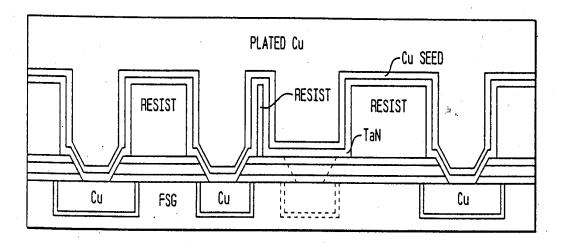
RESIST PATTERN: Tan AND Cu SEED

RESIST RESIST RESIST

Tan

Cu FsG Cu Cu

FIG. 6C



 $FIG.\ 6D$  Cu CMP OR ELECTROPLATING. Tan, CMP OR RIE

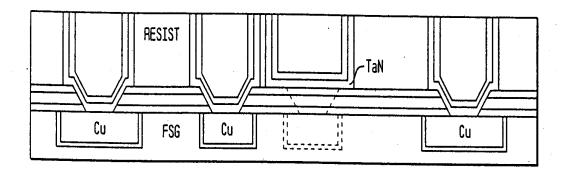


FIG. 6E RESIST STRIP

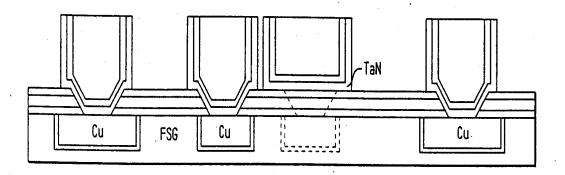


FIG. 7A SELECTIVE METAL ONLY

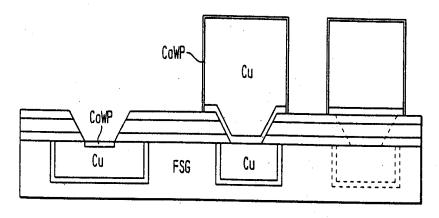


FIG. 7B
DIELECTRIC DEPOSITION ONLY (SINGLE LAYER OR MULTILAYER)

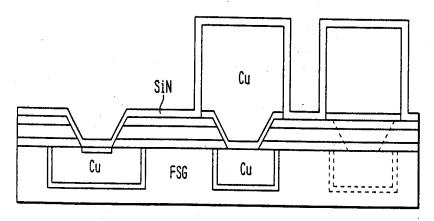


FIG. 7C SELECTIVE METAL AND DIELECTRIC

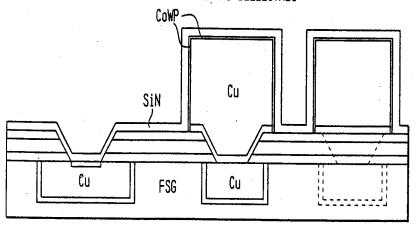


FIG. 7D SPACER (METAL OR INSULATOR) AND DIELECTRIC DEPOSITION

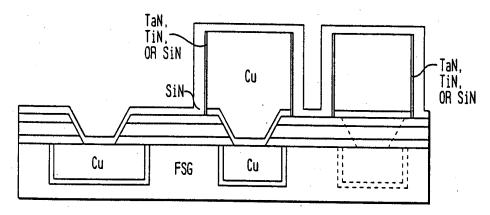


FIG. 7E

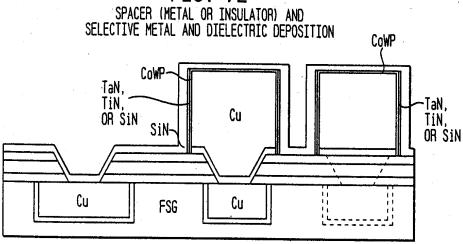


FIG. 7F

